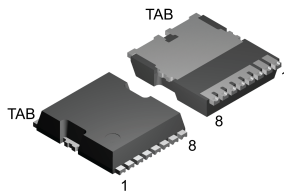
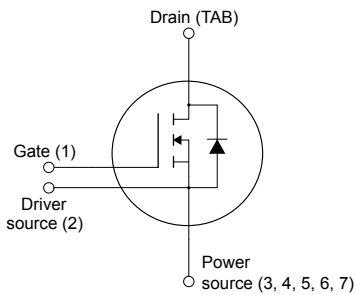


N-channel 600 V, 39 mΩ typ., 55 A, MDmesh DM9 Power MOSFET in a TO-LL package


TO-LL type A2


N-chG1DS2PS34567DTAB


Product status link
[STO60N045DM9](#)
Product summary

Order code	STO60N045DM9
Marking	60N045DM9
Package	TO-LL type A2
Packing	Tape and reel

Features

Order code	V _{DS}	R _{DS(on)} max.	I _D
STO60N045DM9	600 V	45 mΩ	55 A

- Fast-recovery body diode
- Very low FOM (R_{DS(on)}*Q_g)
- Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Excellent switching performance thanks to the extra driving source pin

Applications

- LLC resonant converter
- Power supplies and converters

Description

This N-channel Power MOSFET is based on the most innovative super-junction MDmesh DM9 technology, suitable for medium/high voltage MOSFETs featuring very low R_{DS(on)} per area coupled with a fast-recovery diode. The silicon-based DM9 technology benefits from a multi-drain manufacturing process which allows an enhanced device structure. The fast-recovery diode featuring very low recovery charge (Q_{rr}), time (t_{rr}) and R_{DS(on)} makes this fast-switching super-junction Power MOSFET tailored for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	±30	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	55	A
	Drain current (continuous) at T _C = 100 °C	35	
I _{DM} ⁽²⁾	Drain current (pulsed)	220	A
P _{TOT}	Total power dissipation at T _C = 25 °C	245	W
dv/dt ³	Peak diode recovery voltage slope	120	V/ns
di/dt ³	Peak diode recovery current slope	1300	A/μs
dv/dt ⁽⁴⁾	MOSFET dv/dt ruggedness	120	V/ns
T _{stg}	Storage temperature range	-55 to 150	°C
T _J	Operating junction temperature range		°C

1. Referred to TO-247 long leads package.
2. Pulse width limited by safe operating area.
3. $I_{SD} \leq 28$ A, $V_{DS} (peak) < V_{(BR)DSS}$, $V_{DD} = 400$ V.
4. $V_{DS} (peak) < V_{(BR)DSS}$, $V_{DD} = 400$ V.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thJC}	Thermal resistance, junction-to-case	0.51	°C/W
R _{thJA}	Thermal resistance, junction-to-ambient ⁽¹⁾	43	°C/W
	Thermal resistance, junction-to-ambient ⁽²⁾	22	

1. When mounted on a standard 1 inch² area of FR-4 PCB with 2-oz copper.
2. When mounted on 40x40 mm area of FR-4 PCB with 2-oz copper.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T _J max.)	6	A
E _{AS}	Single pulse avalanche energy (starting T _J = 25 °C, I _D = I _{AR} , V _{DD} = 100 V)	839	mJ

2 Electrical characteristics

$T_C = 25\text{ °C}$ unless otherwise specified.

Table 4. On/off-states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$			5	μA
		$V_{GS} = 0\text{ V}$, $V_{DS} = 600\text{ V}$, $T_C = 125\text{ °C}$ ⁽¹⁾			200	
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 25\text{ V}$			± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	3.5	4.0	4.5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 28\text{ A}$		39	45	m Ω

1. Specified by design, not tested in production.

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 400\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	4675	-	pF
C_{oss}	Output capacitance		-	82	-	pF
$C_{oss\ eq.}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0\text{ to }400\text{ V}$, $V_{GS} = 0\text{ V}$	-	729	-	pF
R_G	Intrinsic gate resistance	$f = 1\text{ MHz}$, open drain	-	0.78	-	Ω
Q_g	Total gate charge	$V_{DD} = 400\text{ V}$, $I_D = 28\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	78.6	-	nC
Q_{gs}	Gate-source charge		-	29	-	nC
Q_{gd}	Gate-drain charge		-	20	-	nC

1. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to stated value.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}$, $I_D = 28\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$	-	27	-	ns
t_r	Rise time		-	6	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	68	-	ns
t_f	Fall time		-	5	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		55	A
$I_{SDM}^{(2)}$	Source-drain current (pulsed)		-		220	A
$V_{SD}^{(3)}$	Forward on voltage	$V_{GS} = 0\text{ V}$, $I_{SD} = 56\text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 56\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 60\text{ V}$	-	165		ns
Q_{rr}	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	1.06		μC
I_{RRM}	Reverse recovery current		-	11		A
t_{rr}	Reverse recovery time	$I_{SD} = 56\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$,	-	220		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 60\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$	-	2.2		μC
I_{RRM}	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	18		A

1. Referred to TO-247 long leads package.
2. Pulse width is limited by safe operating area.
3. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

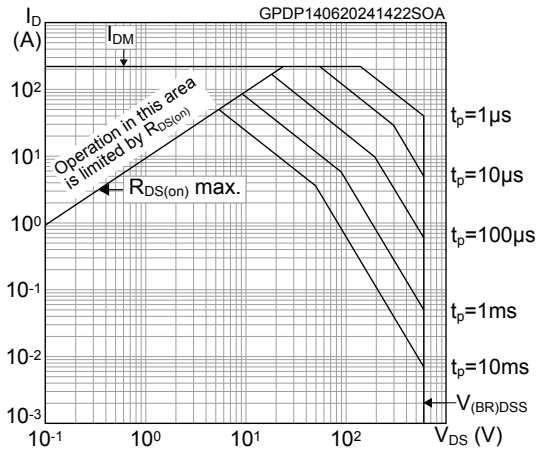


Figure 2. Maximum transient thermal impedance

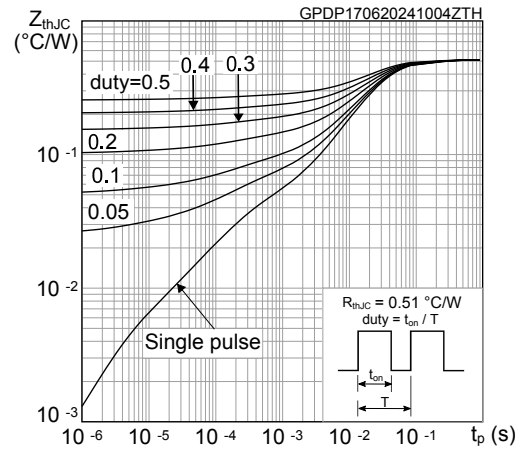


Figure 3. Typical output characteristics

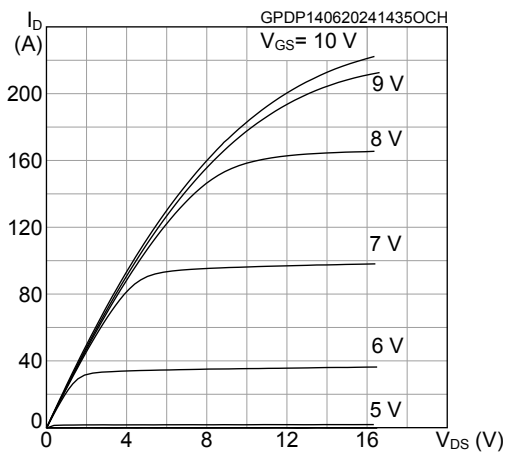


Figure 4. Typical transfer characteristics

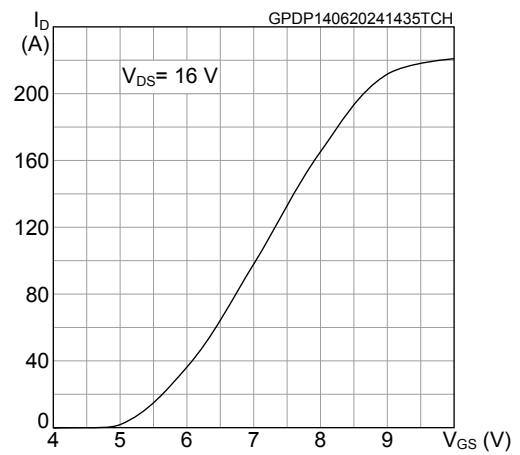


Figure 5. Typical gate charge characteristics

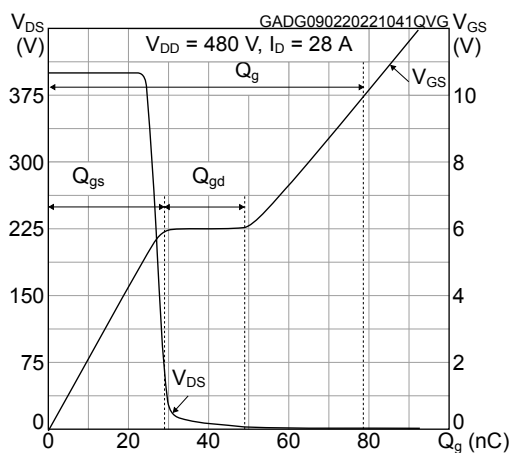


Figure 6. Typical drain-source on-resistance

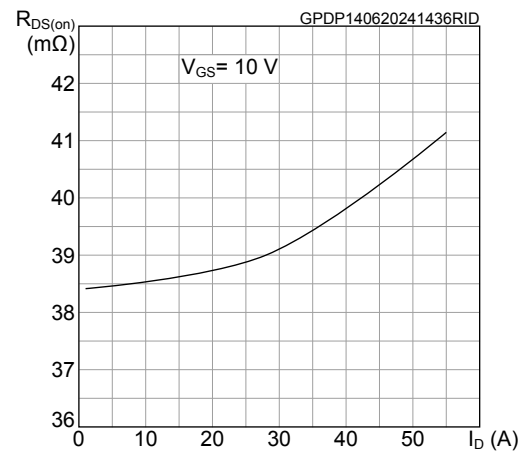


Figure 7. Typical capacitance characteristics

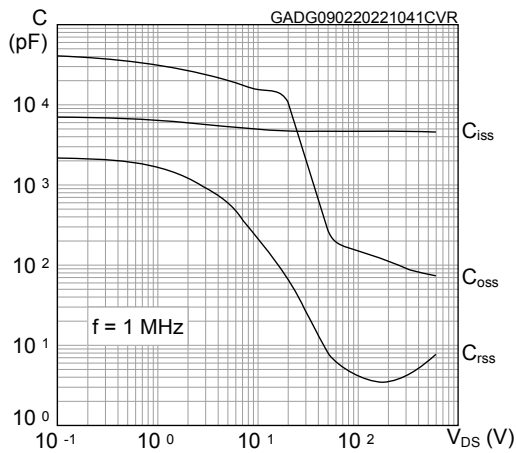


Figure 8. Typical output capacitance stored energy

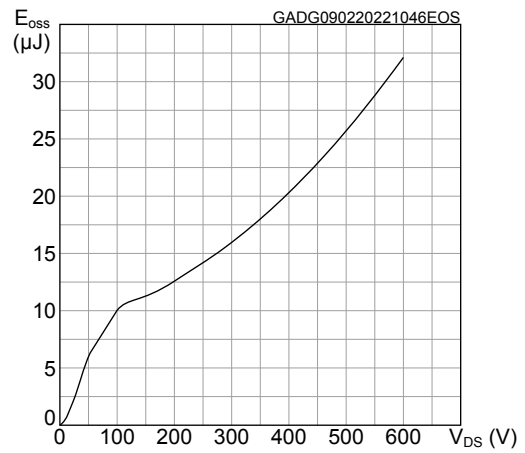


Figure 9. Normalized gate threshold vs temperature

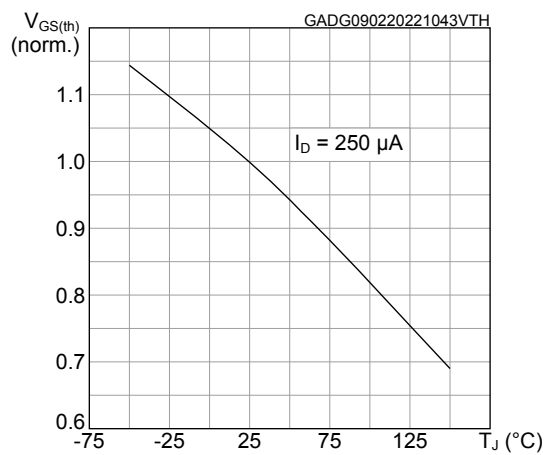


Figure 10. Normalized on-resistance vs temperature

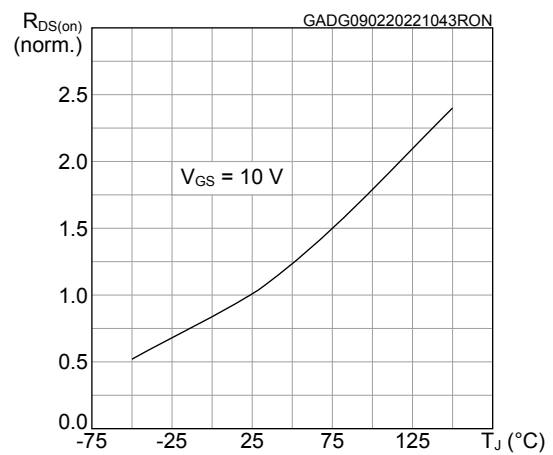


Figure 11. Normalized breakdown voltage vs temperature

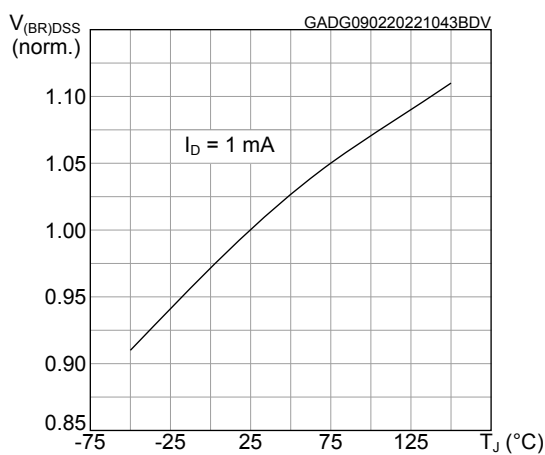
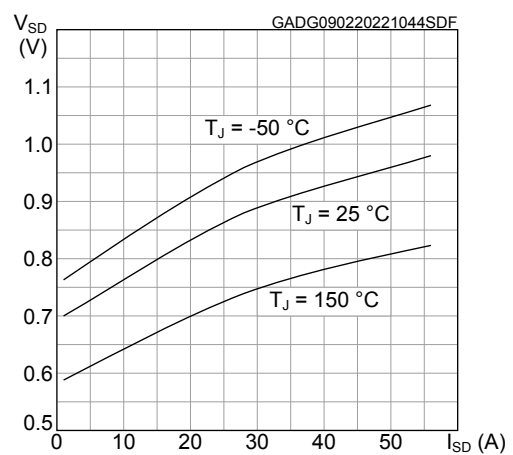
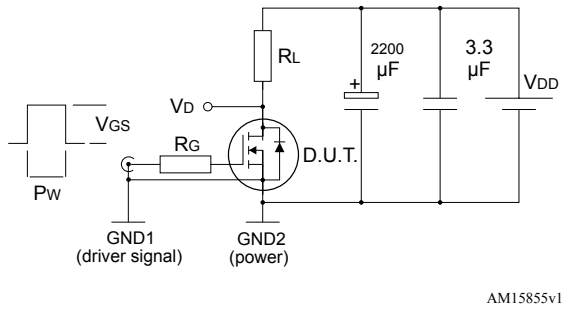
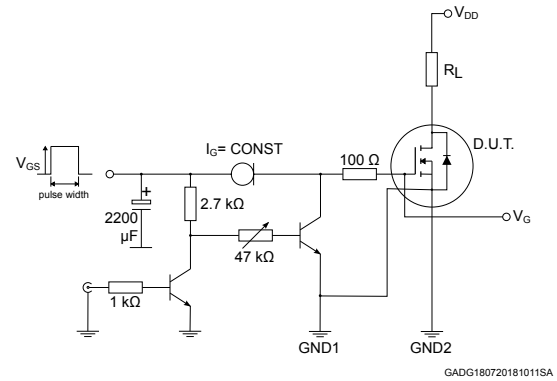
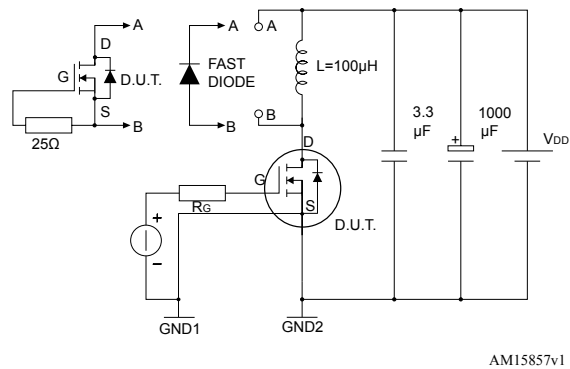
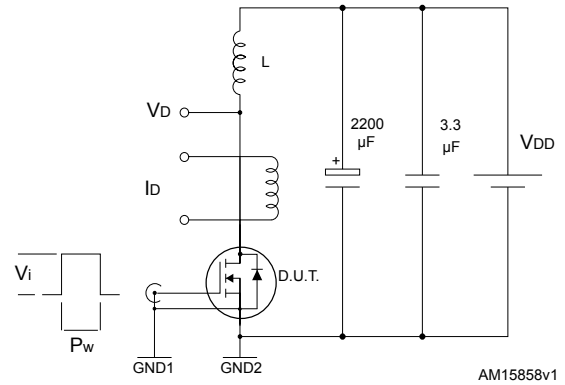
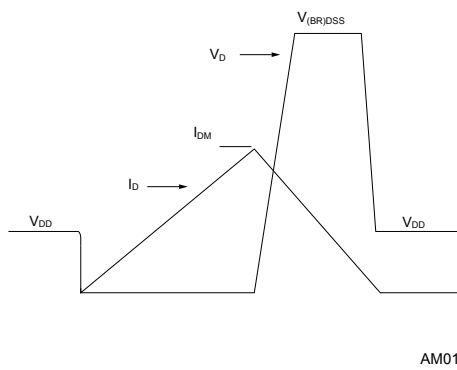
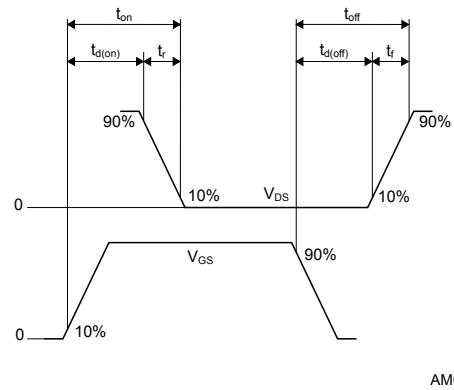


Figure 12. Typical reverse diode forward characteristics



3 Test circuits

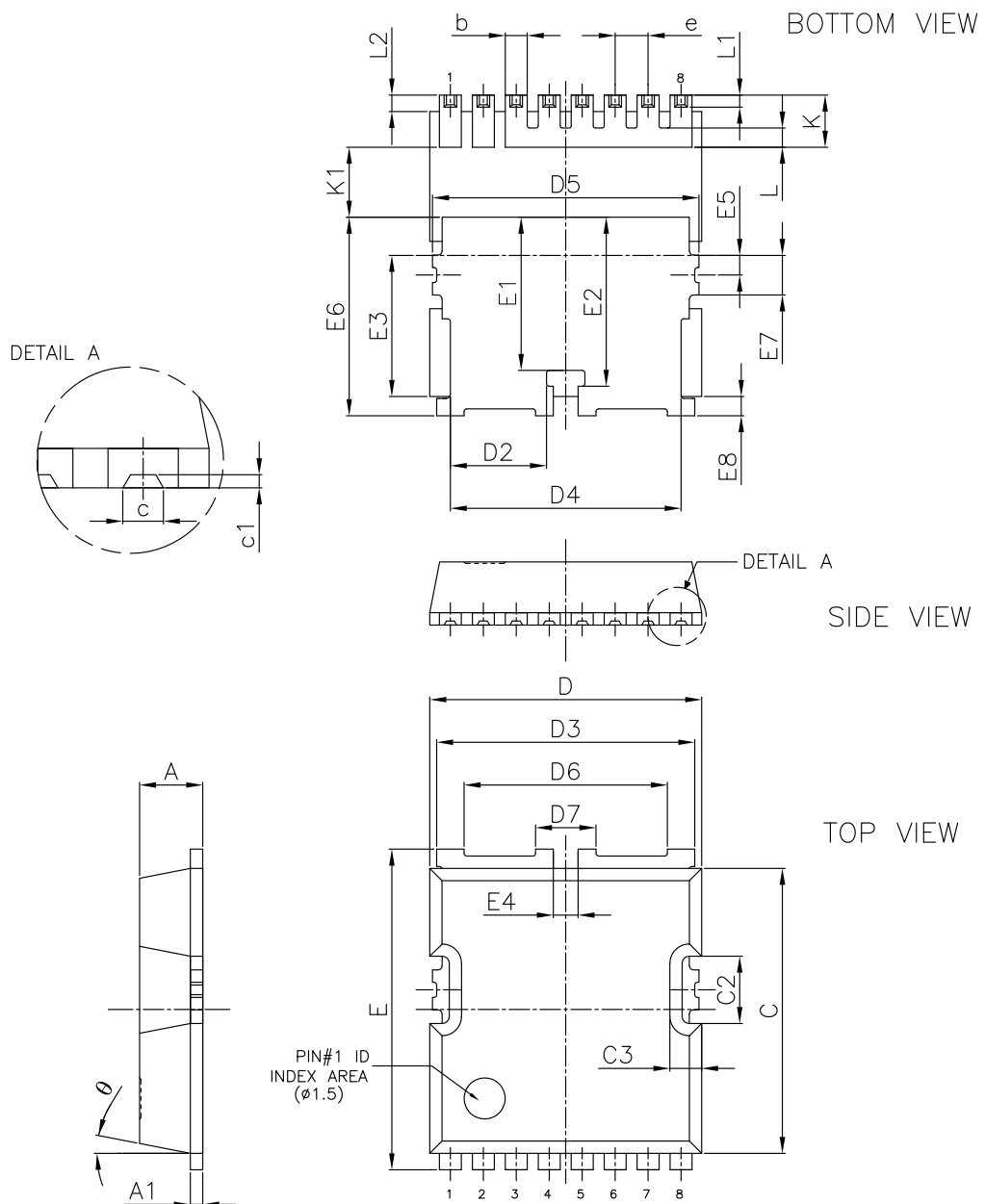
Figure 13. Switching times test circuit for resistive load

Figure 14. Test circuit for gate charge behavior

Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform


4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-LL type A2 package information

Figure 19. TO-LL type A2 package outline

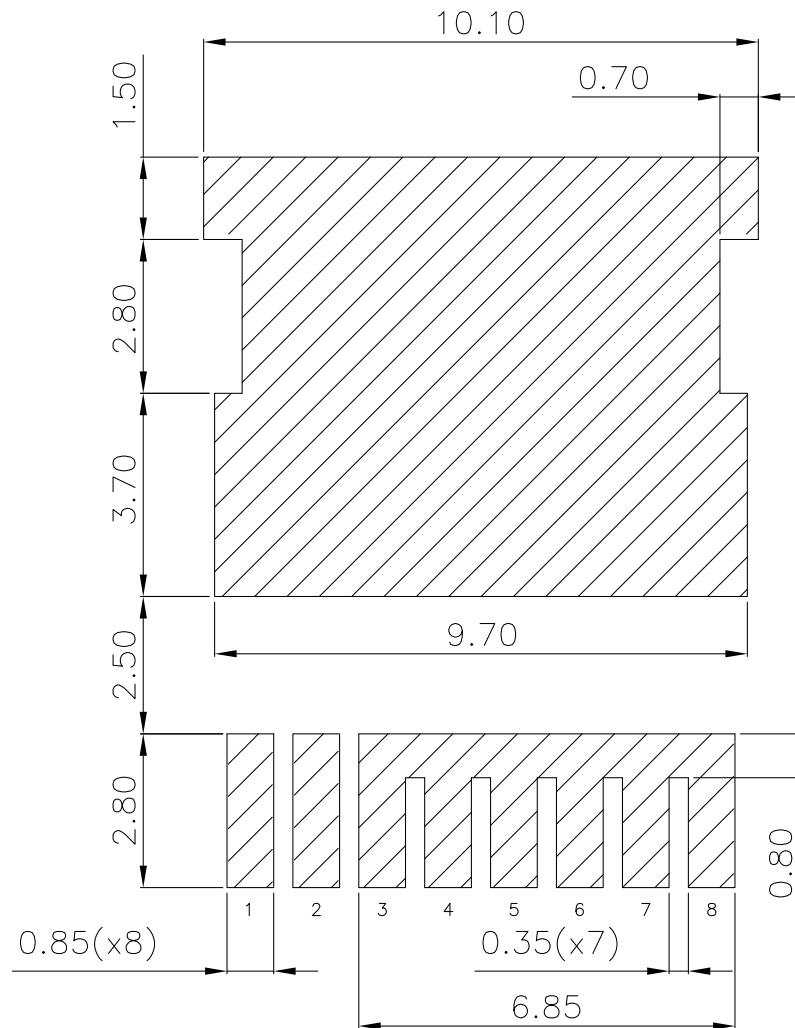


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Table 8. TO-LL type A2 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.40
A1	0.40	0.48	0.60
b	0.70	0.80	0.90
c		0.46	
c1		0.15	
C	10.28	10.38	10.48
C2	2.35	2.45	2.55
C3		1.16	
D	9.80	9.90	10.00
D2	3.30	3.50	3.70
D3	9.30	9.40	9.50
D4	8.20	8.40	8.60
D5	9.50	9.70	9.90
D6		7.40	
D7		2.20	
e		1.20	
E	11.48	11.68	11.88
E1		5.58	
E2		6.15	
E3		5.14	
E4		0.90	
E5		0.72	
E6	7.03	7.23	7.43
E7		1.44	
E8	0.50	0.70	0.90
K	1.70	1.90	2.10
K1	2.40		
L		0.70	
L1		0.44	
L2	0.40	0.60	0.80
θ		11°	

Figure 20. TO-LL type A2 recommended footprint (dimensions are in mm)



DM00276569_7_type_A2

4.2 TO-LL packing information

Figure 21. Carrier tape outline and dimensions

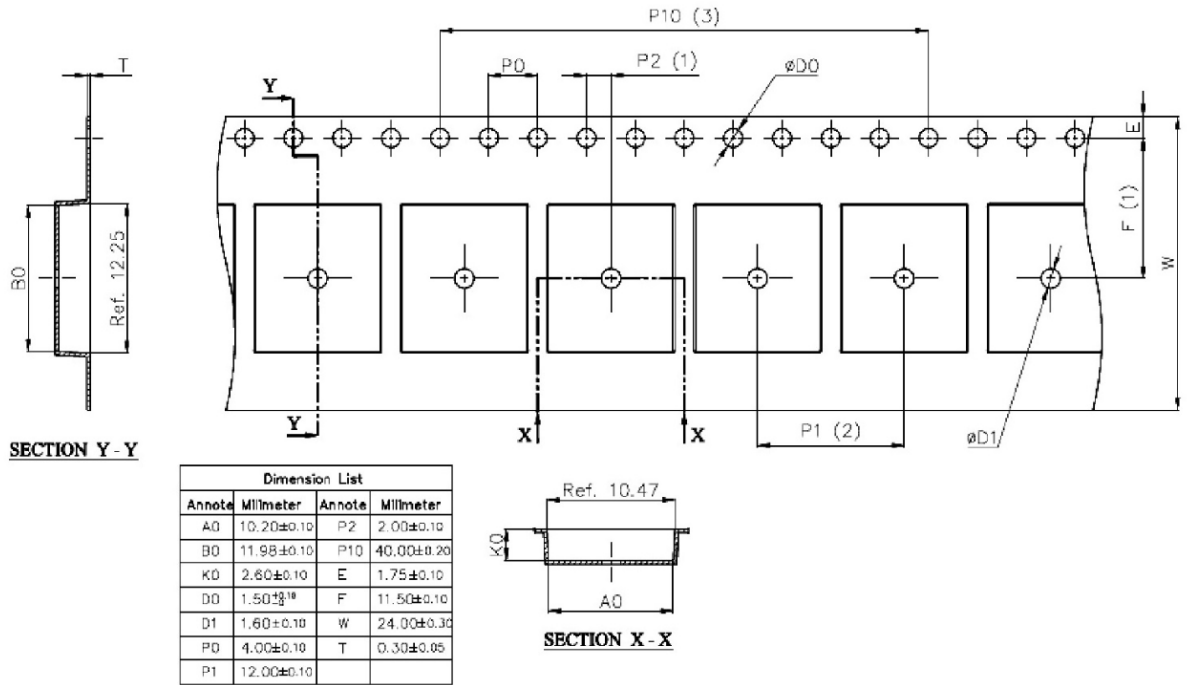


Figure 22. Reel outline and dimensions

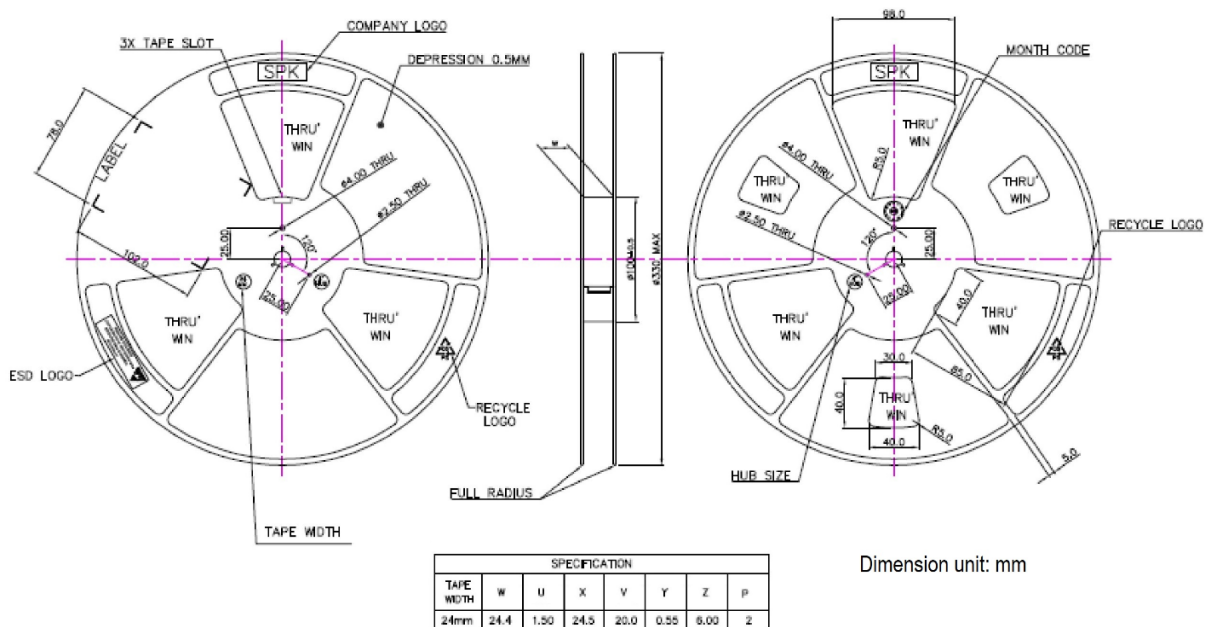
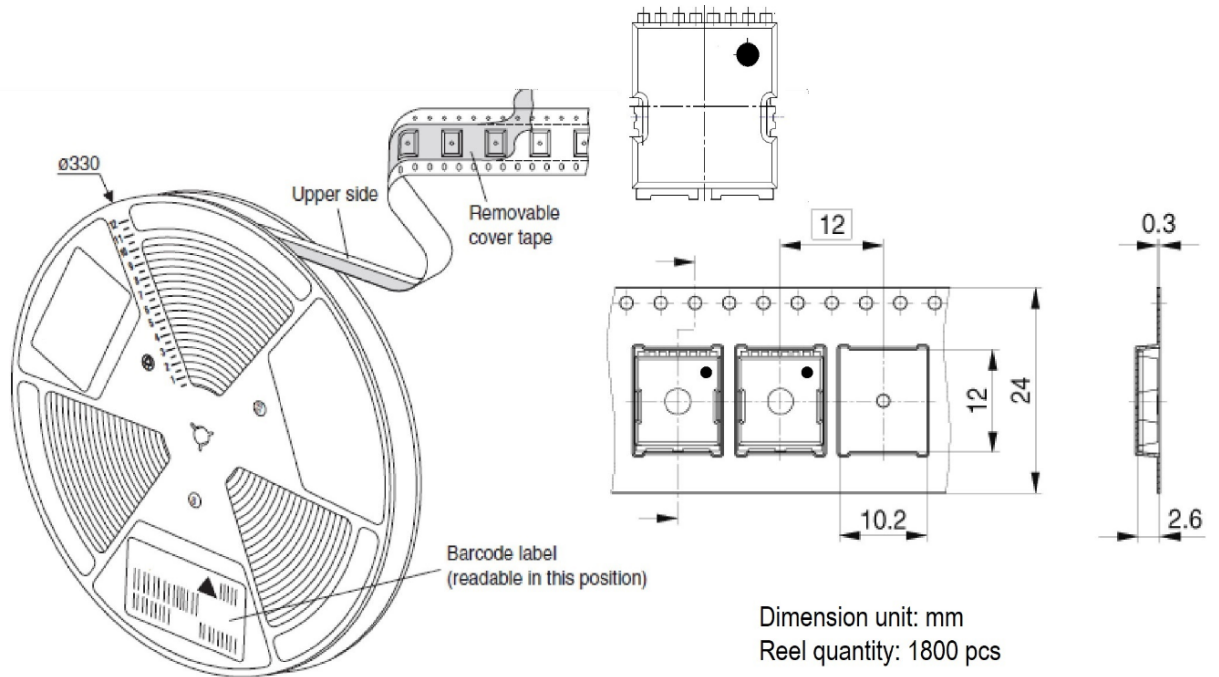


Figure 23. TO-LL orientation in tape pocket



Revision history

Table 9. Document revision history

Date	Revision	Changes
18-Jun-2024	1	First release.
25-Oct-2024	2	Updated package type from TO-LL type A to TO-LL type A2. Updated Section Features and Section 4.1: TO-LL type A2 package information . Minor text changes.

Contents

1	Electrical ratings	2
2	Electrical characteristics	3
2.1	Electrical characteristics (curves)	5
3	Test circuits	7
4	Package information	8
4.1	TO-LL type A2 package information	8
4.2	TO-LL packing information	11
	Revision history	13

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